

Notice of References Cited	Application/Control No. 09/945,108		Applicant(s)/Patent Under Reexamination KIM ET AL.	
	Examiner Chris Parry		Art Unit 2614	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,460,183	10-2002	Van Der Vleuten, Renatus J.	725/139
	B	US-6,359,580	03-2002	Morrison, Hugh Boyd	348/731
	C	US-5,917,481	06-1999	Rzeszewski et al.	715/721
	D	US-6,144,376	11-2000	Connelly, Jay	725/44
	E	US-5,444,499	08-1995	Saitoh, Mitsumasa	348/734
	F	US-6,467,093	10-2002	Inoue et al.	725/151
	G	US-6,766,528	07-2004	Kim et al.	725/113
	H	US-2002/0056098	05-2002	WHITE, CHRISTOPHER M.	725/39
	I	US-2002/0100055	07-2002	Zeidman, Robert M.	725/110
	J	US-2002/0188948	12-2002	Florence, Michael	725/46
	K	US-2003/0066083	04-2003	Hata et al.	725/80
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 9859282 A2	12-1998	World Intellect	HUMPLEMAN et al.	G06F 0/
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IEEE 100: The Authoritative Dictionary Of IEEE Standards Terms, December 2000, Seventh Edition, Page 239.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.